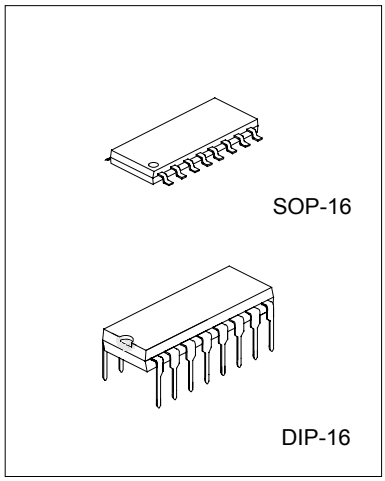
BCD-TO-SEVEN SEGMENT LATCH/DECODER/DRIVER



DESCRIPTION

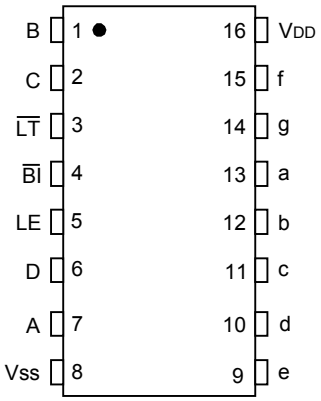
The UTC MC14511 BCD–to–seven segment latch/decoder/driver is constructed with complementary MOS (CMOS) enhancement mode devices and NPN bipolar output drivers in a single monolithic structure. The circuit provides the functions of a 4-bit storage latch, an 8421 BCD-to-seven segment decoder, and an output drive capability. Lamp test ($\overline{LT}$), blanking ($\overline{BI}$), and latch enable (LE) inputs are used to test the display, to turn-off or pulse modulate the brightness of the display, and to store a BCD code, respectively. It can be used with seven-segment light-emitting diodes (LED), incandescent, fluorescent, gas discharge, or liquid crystal readouts either directly or indirectly.

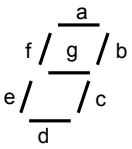
Applications include instrument (e.g., counter, DVM, etc.) display driver, computer/calculator display driver, cockpit display driver, and various clock, watch, and timer uses.

FEATURES

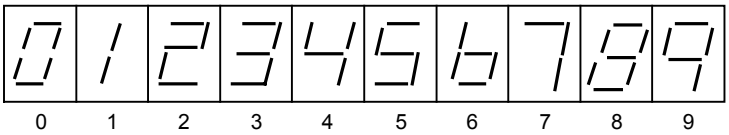
* Low Logic Circuit Power Dissipation
* High–Current Sourcing Outputs (Up to 25 mA)
* Latch Storage of Code
* Blanking Input
* Lamp Test Provision
* Readout Blanking on all Illegal Input Combinations
* Lamp Intensity Modulation Capability
* Time Share (Multiplexing) Facility
* Supply Voltage Range = 3.0 V ~ 18 V
* Capable of Driving Two Low-power TTL Loads, One Low-power Schottky TTL Load or Two HTL Loads Over the Rated Temperature Range
* Chip Complexity: 216 FETs or 54 Equivalent Gates
* Triple Diode Protection on all Inputs

PIN CONFIGURATION





DISPLAY



TRUTH TABLE

Inputs							Outputs							
LE	BI	LT	D	C	B	A	a	b	c	d	e	f	g	Display
X	X	0	X	X	X	X	1	1	1	1	1	1	1	8
X	0	1	X	X	X	X	0	0	0	0	0	0	0	Blank
0	1	1	0	0	0	0	1	1	1	1	1	1	0	0
0	1	1	0	0	0	1	0	1	1	0	0	0	0	1
0	1	1	0	0	1	0	1	1	0	1	1	0	1	2
0	1	1	0	0	1	1	1	1	1	1	0	0	1	3
0	1	1	0	1	0	0	0	1	1	0	0	1	1	4
0	1	1	0	1	0	1	1	0	1	1	0	1	1	5
0	1	1	0	1	1	0	0	0	1	1	1	1	1	6
0	1	1	0	1	1	1	1	1	1	0	0	0	0	7
0	1	1	1	0	0	0	1	1	1	1	1	1	1	8
0	1	1	1	0	0	1	1	1	1	0	0	1	1	9
0	1	1	1	0	1	0	0	0	0	0	0	0	0	Blank
0	1	1	1	0	1	1	0	0	0	0	0	0	0	Blank
0	1	1	1	1	0	0	0	0	0	0	0	0	0	Blank
0	1	1	1	1	0	1	0	0	0	0	0	0	0	Blank
0	1	1	1	1	1	0	0	0	0	0	0	0	0	Blank
0	1	1	1	1	1	1	0	0	0	0	0	0	0	Blank
1	1	1	X	X	X	X	*							*

X=Don't Care

*Depends upon the BCD code previously applied when LE=0

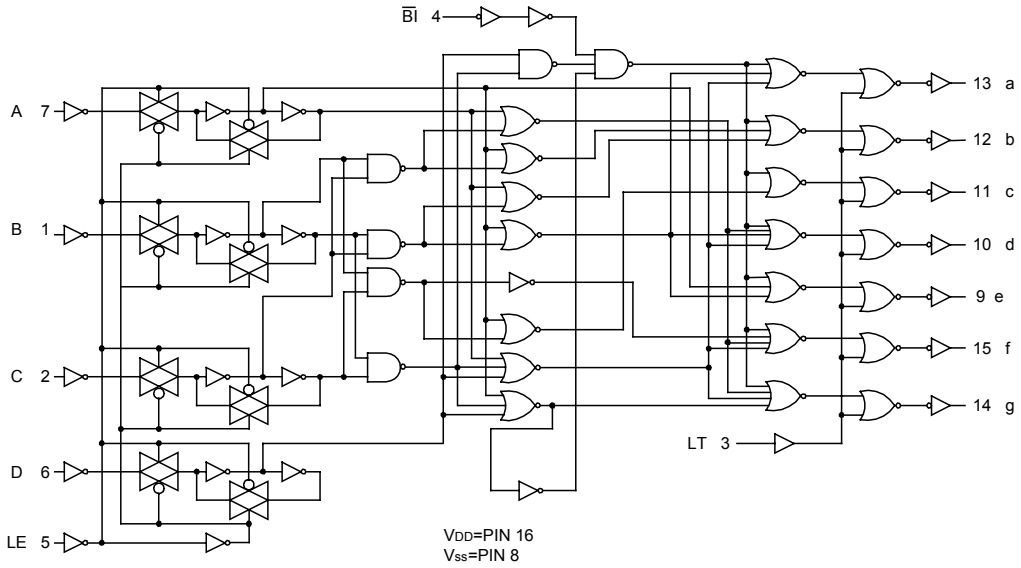
This device contains protection circuitry to protect the inputs against damage due to high static voltages or electric fields. However, it is advised that normal precautions be taken to avoid application of any voltage higher than maximum rated voltages to this high-impedance circuit. A destructive high current mode may occur if V_{in} and V_{out} are not constrained to the range:

$V_{SS} \leqslant (V_{in}$ or $V_{out}) \leqslant V_{DD}$.

Due to the sourcing capability of this circuit, damage can occur to the device if V_{DD} is applied, and the outputs are shorted to V_{SS} and are at a logical 1 (See Maximum Ratings).

Unused inputs must always be tied to an appropriate logic voltage level (e.g., either V_{SS} or V_{DD}).

BLOCK DIAGRAM



ABSOLUTE MAXIMUM RATINGS (Voltages Referenced to Vss) (Note 1)

PARAMETER	SYMBOL	RATINGS	UNIT
DC Supply Voltage Range	V_{DD}	-0.5 ~ +18.0	V
Input Voltage Range, All Inputs	Vin	-0.5 ~ V_{DD}+0.5	V
DC Current Drain per Input Pin	I	10	mA
Power Dissipation, per Package (Note 2)	P_D	500	mW
Maximum Output Drive Current (Source) per Output	I_{OHmax}	25	mA
Maximum Continuous Output Power (Source) per Output (Note 3)	P_{OHmax}	50	mA
Operating Temperature Range	T_a	-55 ~ +125	℃
Storage Temperature Range	Tstg	-65 ~ +150	℃

Note 1: Maximum Ratings are those values beyond which damage to the device may occur.

Note 2: Temperature Derating:
Plastic "P and D/DW" Packages: - 7.0 mW/℃ From 65℃ ~ 125℃

Note 3: $P_{OHmax} = I_{OH} (V_{DD} – V_{OH})$

ELECTRICAL CHARACTERISTICS (Voltages Referenced to Vss)

PARAMETER	SYMBOL	V_{DD} Vdc	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Output Voltage	V_{OL}	5.0 10 15	"0" Level Vin=V_{DD} or 0		0 0 0	0.05 0.05 0.05	V
	V_{OH}	5.0 10 15	"1" Level Vin=0 or V_{DD}	4.1 9.1 14.1	4.57 9.58 14.59		V
Input Voltage #	V_{IL}	5.0 10 15	"0" Level Vo=3.8 or 0.5 V Vo=8.8 or 1.0 V Vo=13.8 or 1.5V		2.25 4.50 6.75	1.5 3.0 4.0	V
	V_{IH}	5.0 10 15	"1" Level Vo=0.5 or 3.8 V Vo=1.0 or 8.8 V Vo=1.5 or 13.8 V	3.5 7.0 11	2.75 5.50 8.25		V
Output Drive Voltage	V_{OH}	5.0	I_{OH}=0mA Source I_{OH}=5.0mA I_{OH}=10mA I_{OH}=15mA I_{OH}=20mA I_{OH}=25mA	4.1 3.9 3.4 	4.57 4.24 4.12 3.94 3.70 3.54		V
		10	I_{OH}=0mA Source I_{OH}=5.0mA I_{OH}=10mA I_{OH}=15mA I_{OH}=20mA I_{OH}=25mA	9.1 9.0 8.6 	9.58 9.26 9.17 9.04 8.90 8.70		V

PARAMETER	SYMBOL	V_{DD} Vdc	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Output Drive Voltage	V_{OH}	15	I_{OH}=0mA Source I_{OH}=5.0mA I_{OH}=10mA I_{OH}=15mA I_{OH}=20mA I_{OH}=25mA	14.1 14 13.6 	14.59 14.27 14.18 14.07 13.95 13.70		V
Output Drive Current	I_{OL}	5.0 10 15	V_{OL}=0.4V Sink V_{OL}=0.5V V_{OL}=1.5V	0.51 1.3 3.4	0.88 2.25 8.8		mA
Input Current	I_{in}	15			±0.00001	±0.1	μA
Input Capacitance	C_{in}				5.0	7.5	pF
Quiescent Current	I_{DD}	5.0 10 15	(Per Package) Vin=0 or V_{DD}, Iout=0 μA		0.005 0.010 0.015	5.0 10 20	μA
Total Supply Current (Notes 5 & 6)	I_T	5.0 10 15	(Dynamic plus Quiescent, Per Package) (C_L=50pF on all outputs, all buffers switching)	I_T=(1.9 μA/kHz) f+I_{DD} I_T=(3.8 μA/kHz) f+I_{DD} I_T=(5.7 μA/kHz) f+I_{DD}			μA

Note 4: Noise immunity specified for worst–case input combination.
Noise Margin for both “1” and “0” level =
1.0 V min @ V_{DD} = 5.0 V
2.0 V min @ V_{DD} = 10 V
2.5 V min @ V_{DD} = 15 V

Note 5: The formulas given are for the typical characteristics only at 25℃.

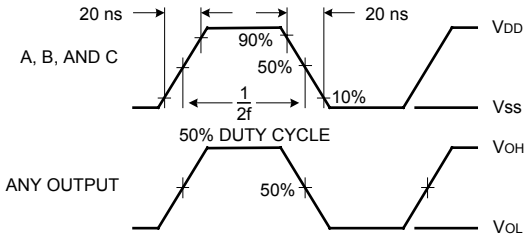
Note 6: To calculate total supply current at loads other than 50 pF:
$I_T(C_L) = I_T(50\ pF) + 3.5 \times 10^{-3} (C_L - 50) V_{DD} f$
Where: I_T is in μA (per package), C_L in pF, V_{DD} in Vdc, and f in kHz is input frequency.

SWITCHING CHARACTERISTICS (Note 7) (C_L=50pF, T_a=25℃)

PARAMETER	SYMBOL	V_{DD} Vdc	TEST CONDITIONS	Min	TYP	MAX	UNIT
Output Rise Time	t_{TLH}	5.0	t_{TLH}=(0.40 ns/pF) C_L+20 ns		40	80	ns
		10	t_{TLH}=(0.25 ns/pF) C_L+17.5 ns		30	60	
		15	t_{TLH}=(0.20 ns/pF) C_L+15 ns		25	50	
Output Fall Time	t_{THL}	5.0	t_{THL}=(1.5 ns/pF) C_L+50 ns		125	250	ns
		10	t_{THL}=(0.75 ns/pF) C_L+37.5 ns		75	150	
		15	t_{THL}=(0.55 ns/pF) C_L+37.5 ns		65	130	
Data Propagation Delay Time	t_{PLH}	5.0	t_{PLH}=(0.40 ns/pF) C_L+620 ns		640	1280	ns
		10	t_{PLH}=(0.25 ns/pF) C_L+237.5 ns		250	500	
		15	t_{PLH}=(0.20 ns/pF) C_L+165 ns		175	350	
	t_{PHL}	5.0	t_{PHL}=(1.3 ns/pF) C_L+655 ns		720	1440	
		10	t_{PHL}=(0.60 ns/pF) C_L+260 ns		290	580	
		15	t_{PHL}=(0.35 ns/pF) C_L+182.5 ns		200	400	
$\overline{\text{Blank}}$ Propagation Delay Time	t_{PLH}	5.0	t_{PLH}=(0.30 ns/pF) C_L+585 ns		600	750	ns
		10	t_{PLH}=(0.25 ns/pF) C_L+187.5 ns		200	300	
		15	t_{PLH}=(0.15 ns/pF) C_L+142.5 ns		150	220	
	t_{PHL}	5.0	t_{PHL}=(0.85 ns/pF) C_L+442.5 ns		485	970	
		10	t_{PHL}=(0.45 ns/pF) C_L+177.5 ns		200	400	
		15	t_{PHL}=(0.35 ns/pF) C_L+142.5 ns		160	320	
$\overline{\text{Lamp Test}}$ Propagation Delay Time	t_{PLH}	5.0	t_{PLH}=(0.45 ns/pF) C_L+290.5 ns		313	625	ns
		10	t_{PLH}=(0.25 ns/pF) C_L+112.5 ns		125	250	
		15	t_{PLH}=(0.20 ns/pF) C_L+80 ns		90	180	
	t_{PHL}	5.0	t_{PHL}=(1.3 ns/pF) C_L+248 ns		313	625	
		10	t_{PHL}=(0.45 ns/pF) C_L+102.5 ns		125	250	
		15	t_{PHL}=(0.35 ns/pF) C_L+72.5 ns		90	180	
Setup Time	t_{su}	5.0		100			ns
		10		40			
		15		30			
Hold Time	t_h	5.0		60			ns
		10		40			
		15		30			
Latch Enable Pulse Width	t_{WL}	5.0		520	260		ns
		10		220	110		
		15		130	65		

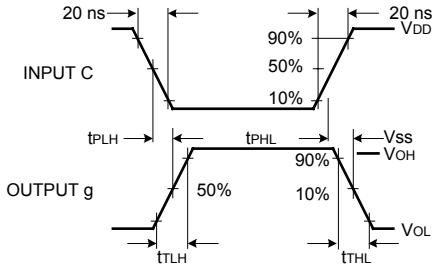
Note 7: The formulas given are for the typical characteristics only.

SWITCHING TIME WAVEFORMS

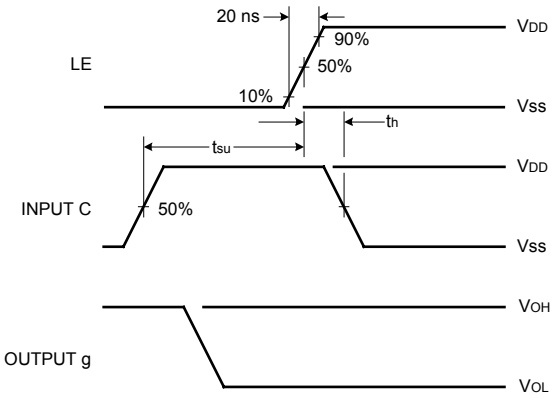


Input LE low, and Inputs D, $\overline{BI}$ and $\overline{LT}$ high.
f in respect to a system clock.
All outputs connected to respective C_L loads.

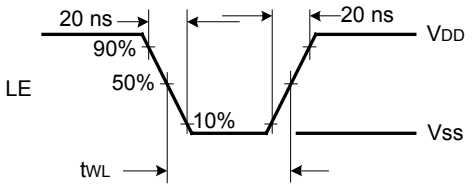
Figure 1. Dynamic Power Dissipation Signal Waveforms



(a) Inputs D and LE low, and Inputs A, B, $\overline{BI}$ and $\overline{LT}$ high



(b) Input D low, Inputs A, B, $\overline{BI}$ and $\overline{LT}$ high

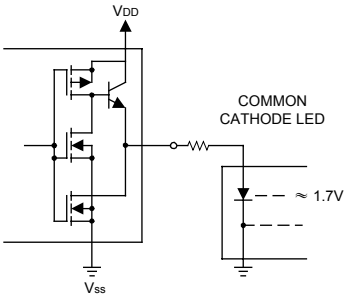


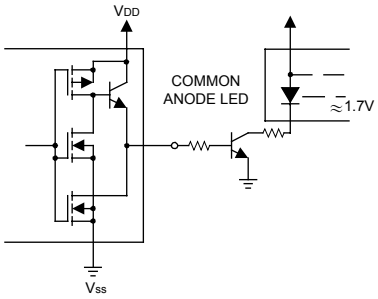
(c) Data DCBA strobed into latches.

Figure 2. Dynamic Signal Waveforms

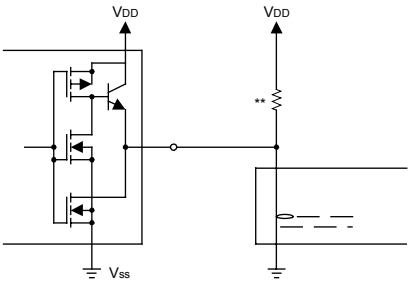
CONNECTIONS TO VARIOUS DISPLAY READOUTS

LIGHT EMITTING DIODE (LED) READOUT

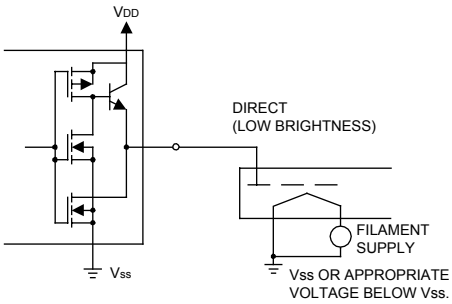




INCANDESCENT READOUT

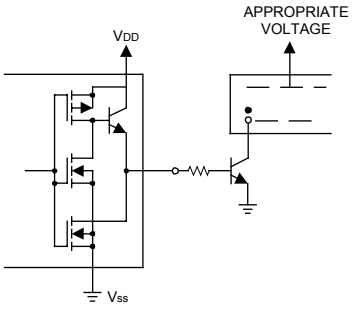


FLUORESCENT READOUT



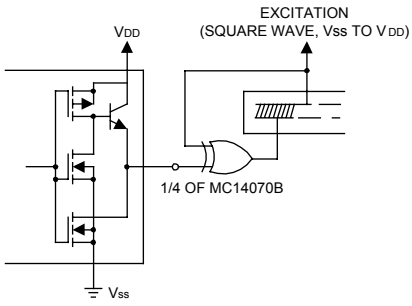
(CAUTION: Maximum working voltage=18.0V)

GAS DISCHARGE READOUT



** A filament pre-warm resistor is recommended to reduce filament thermal shock and increase the effective cold resistance of the filament.

LIQUID CRYSTAL(LCD) READOUT



Direct dc drive of LCD's not recommended for life of LCD readouts.

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